

N-channel 30 V 1.3 mΩ logic level MOSFET in I2PAK 2 April 2014 Product d

Product data sheet

### 1. General description

Logic level N-channel MOSFET in I2PAK package qualified to 175 °C. This product is designed and qualified for use in a wide range of industrial, communications and domestic equipment.

### 2. Features and benefits

- High efficiency due to low switching and conduction losses
- Suitable for logic level gate drive sources

### 3. Applications

- DC-to-DC converters
- Load switiching
- Motor control
- Server power supplies

### 4. Quick reference data

Table 1. Q	uick reference data						
Symbol	Parameter	Conditions		Min	Тур	Max	Unit
V <sub>DS</sub>	drain-source voltage	T <sub>j</sub> ≥ 25 °C; T <sub>j</sub> ≤ 175 °C		-	-	30	V
I <sub>D</sub>	drain current	T <sub>mb</sub> = 25 °C; V <sub>GS</sub> = 10 V; <u>Fig. 2</u>	[1]	-	-	120	А
P <sub>tot</sub>	total power dissipation	T <sub>mb</sub> = 25 °C; <u>Fig. 1</u>		-	-	338	W
Tj	junction temperature			-55	-	175	°C
Static chara	cteristics						
R <sub>DSon</sub>	drain-source on-state resistance	V <sub>GS</sub> = 10 V; I <sub>D</sub> = 25 A; T <sub>j</sub> = 25 °C; Fig. 12	[2]	-	1.1	1.3	mΩ
		V <sub>GS</sub> = 10 V; I <sub>D</sub> = 25 A; T <sub>j</sub> = 100 °C; Fig. 13		-	1.5	1.8	mΩ
Dynamic ch	aracteristics						
Q <sub>GD</sub>	gate-drain charge	$V_{GS}$ = 4.5 V; I <sub>D</sub> = 75 A; V <sub>DS</sub> = 15 V;		-	37	-	nC
Q <sub>G(tot)</sub>	total gate charge	Fig. 14; Fig. 15		-	118	-	nC





# PSMN1R1-30EL

#### N-channel 30 V 1.3 m $\Omega$ logic level MOSFET in I2PAK

Symbol	Parameter	Conditions		Min	Тур	Max	Unit
Avalanche ruggedness						-	
E <sub>DS(AL)S</sub>	non-repetitive drain- source avalanche energy	$\label{eq:VGS} \begin{array}{l} V_{GS} = 10 \; V; \; T_{j(\text{init})} = 25 \; ^{\circ}\text{C}; \; I_{D} = 120 \; A; \\ V_{sup} \leq 30 \; V; \; R_{GS} = 50 \; \Omega; \; \text{unclamped} \end{array}$		-	-	1.9	J

[1] Continuous current is limited by package.

[2] Measured 3 mm from package.

## 5. Pinning information

Table 2.	Pinning	information		
Pin	Symbol	Description	Simplified outline	Graphic symbol
1	G	gate	mb	D
2	D	drain		
3	S	source		G L F A
mb	D	mounting base; connected to drain	1 2 3 12PAK (SOT226)	mbb076 S

### 6. Ordering information

Table 3. Ordering information						
Type number	Package					
	Name	Description	Version			
PSMN1R1-30EL	12PAK	plastic single-ended package (I2PAK); TO-262	SOT226			

### 7. Marking

Table 4. Marking codes	
Type number	Marking code
PSMN1R1-30EL	PSMN1R1-30EL

## 8. Limiting values

#### Table 5.Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

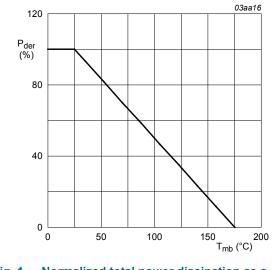
Symbol	Parameter	Conditions		Min	Max	Unit
V <sub>DS</sub>	drain-source voltage	T <sub>j</sub> ≥ 25 °C; T <sub>j</sub> ≤ 175 °C		-	30	V
V <sub>DGR</sub>	drain-gate voltage	$T_j \ge 25 \text{ °C}; T_j \le 175 \text{ °C}; R_{GS} = 20 \text{ k}\Omega$		-	30	V
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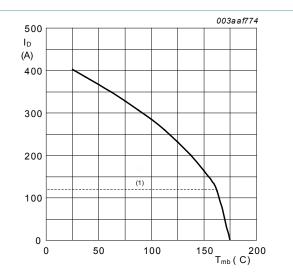
Symbol	Parameter	Conditions		Min	Max	Unit
V <sub>GS</sub>	gate-source voltage			-20	20	V
P <sub>tot</sub>	total power dissipation	T <sub>mb</sub> = 25 °C; <u>Fig. 1</u>		-	338	W
I <sub>D</sub>	drain current	V <sub>GS</sub> = 10 V; T <sub>mb</sub> = 100 °C; <u>Fig. 2</u>	[1]	-	120	А
		V <sub>GS</sub> = 10 V; T <sub>mb</sub> = 25 °C; <u>Fig. 2</u>	[1]	-	120	А
I <sub>DM</sub>	peak drain current	pulsed; $t_p \le 10 \ \mu s$ ; $T_{mb} = 25 \ ^\circ C$ ; Fig. 3		-	1609	Α
T <sub>stg</sub>	storage temperature			-55	175	°C
Tj	junction temperature			-55	175	°C
T <sub>sld(M)</sub>	peak soldering temperature			-	260	°C
Source-drai	in diode					
I <sub>S</sub>	source current	T <sub>mb</sub> = 25 °C	[1]	-	120	А
I <sub>SM</sub>	peak source current	pulsed; $t_p \le 10 \ \mu s$ ; $T_{mb} = 25 \ ^\circ C$		-	1609	А
Avalanche i	ruggedness					
E <sub>DS(AL)S</sub>	non-repetitive drain-source avalanche energy	$V_{GS}$ = 10 V; T <sub>j(init)</sub> = 25 °C; I <sub>D</sub> = 120 A; V <sub>sup</sub> ≤ 30 V; R <sub>GS</sub> = 50 Ω; unclamped		-	1.9	J

[1] Continuous current is limited by package.





$$P_{der} = \frac{P_{tot}}{P_{tot(25^{\circ}C)}} \times 100 \%$$

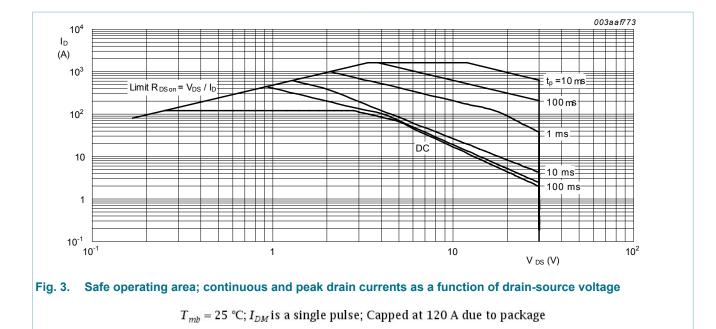


# Fig. 2. Continuous drain current as a function of mounting base temperature.

 $V_{GS} \ge 10 \text{ V}; \quad (1) \text{ Capped at } 120 \text{ A due to package}$ 

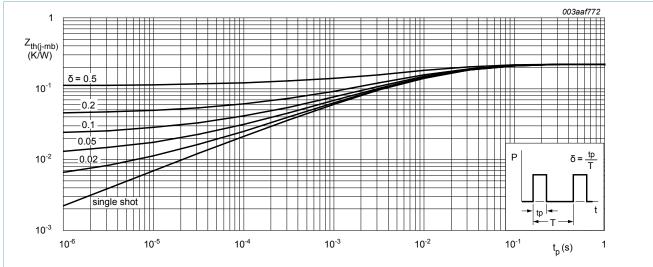
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### 9. Thermal characteristics

Table 6. T	hermal characteristics					
Symbol	Parameter	Conditions	Min	Тур	Max	Unit
R <sub>th(j-mb)</sub>	thermal resistance from junction to mounting base	Fig. 4	-	0.22	0.44	K/W
R <sub>th(j-a)</sub>	thermal resistance from junction to ambient	Vertical in free air	-	60	-	K/W



# Fig. 4. Transient thermal impedance from junction to mounting base as a function of pulse duration; typical values

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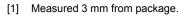
# **10. Characteristics**

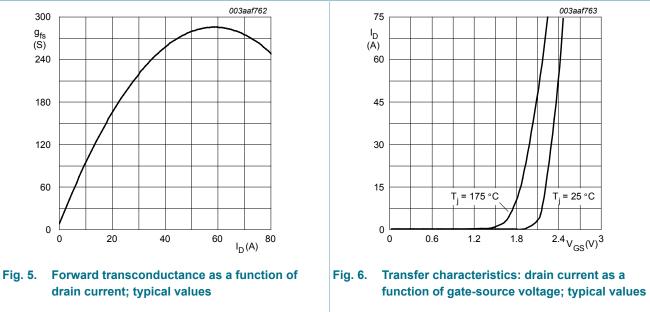
Symbol	Parameter	Conditions		Min	Тур	Max	Unit
Static chara	acteristics						
V <sub>(BR)DSS</sub>	drain-source	$I_D$ = 250 µA; $V_{GS}$ = 0 V; $T_j$ = 25 °C		30	-	-	V
	breakdown voltage	I <sub>D</sub> = 250 μA; V <sub>GS</sub> = 0 V; T <sub>j</sub> = -55 °C		27	-	-	V
V <sub>GS(th)</sub>	gate-source threshold voltage	I <sub>D</sub> = 1 mA; V <sub>DS</sub> = V <sub>GS</sub> ; T <sub>j</sub> = 25 °C; Fig. 10; Fig. 11		1.3	1.7	2.15	V
		I <sub>D</sub> = 2 mA; V <sub>DS</sub> = V <sub>GS</sub> ; T <sub>j</sub> = 175 °C; Fig. 11		0.5	-	-	V
		I <sub>D</sub> = 1 mA; V <sub>DS</sub> = V <sub>GS</sub> ; T <sub>j</sub> = -55 °C; Fig. 11		-	-	2.5	V
DSS	drain leakage current	V <sub>DS</sub> = 30 V; V <sub>GS</sub> = 0 V; T <sub>j</sub> = 25 °C		-	0.02	10	μA
		V <sub>DS</sub> = 30 V; V <sub>GS</sub> = 0 V; T <sub>j</sub> = 175 °C		-	250	500	μA
GSS	gate leakage current	V <sub>GS</sub> = 16 V; V <sub>DS</sub> = 0 V; T <sub>j</sub> = 25 °C		-	10	100	nA
		V <sub>GS</sub> = -16 V; V <sub>DS</sub> = 0 V; T <sub>j</sub> = 25 °C		-	10	100	nA
R <sub>DSon</sub>	drain-source on-state resistance	V <sub>GS</sub> = 10 V; I <sub>D</sub> = 25 A; T <sub>j</sub> = 25 °C; <u>Fig. 12</u>	[1]	-	1.1	1.3	mΩ
		V <sub>GS</sub> = 4.5 V; I <sub>D</sub> = 25 A; T <sub>j</sub> = 25 °C; Fig. 12		-	1.2	1.6	mΩ
		V <sub>GS</sub> = 10 V; I <sub>D</sub> = 25 A; T <sub>j</sub> = 175 °C; Fig. 13; Fig. 12		-	2.1	2.5	mΩ
		V <sub>GS</sub> = 10 V; I <sub>D</sub> = 25 A; T <sub>j</sub> = 100 °C; Fig. 13		-	1.5	1.8	mΩ
R <sub>G</sub>	gate resistance	f = 1 MHz		-	1.1	-	Ω
Dynamic ch	naracteristics	·					
Q <sub>G(tot)</sub>	total gate charge	I <sub>D</sub> = 75 A; V <sub>DS</sub> = 15 V; V <sub>GS</sub> = 10 V; Fig. 14; Fig. 15		-	243	-	nC
		I <sub>D</sub> = 0 A; V <sub>DS</sub> = 0 V; V <sub>GS</sub> = 10 V; Fig. 14; Fig. 15		-	222	-	nC
		$I_D$ = 75 A; $V_{DS}$ = 15 V; $V_{GS}$ = 4.5 V;		-	118	-	nC
Q <sub>GS</sub>	gate-source charge	Fig. 14; Fig. 15		-	39	-	nC
Q <sub>GS(th)</sub>	pre-threshold gate- source charge	-		-	22	-	nC
Q <sub>GS(th-pl)</sub>	post-threshold gate- source charge			-	17	-	nC
ସ୍ <sub>GD</sub>	gate-drain charge			-	37	-	nC
V <sub>GS(pl)</sub>	gate-source plateau voltage	V <sub>DS</sub> = 15 V; <u>Fig. 14;</u> <u>Fig. 15</u>		-	2.8	-	V

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Symbol	Parameter	Conditions	Min	Тур	Max	Unit
C <sub>iss</sub>	input capacitance	$V_{DS}$ = 15 V; $V_{GS}$ = 0 V; f = 1 MHz;	-	14850	-	pF
C <sub>oss</sub>	output capacitance	T <sub>j</sub> = 25 °C; <u>Fig. 16</u>	-	2799	-	pF
C <sub>rss</sub>	reverse transfer capacitance		-	1215	-	pF
t <sub>d(on)</sub>	turn-on delay time	$V_{DS}$ = 15 V; R <sub>L</sub> = 0.2 Ω; V <sub>GS</sub> = 4.5 V;	-	95	-	ns
t <sub>r</sub>	rise time	$R_{G(ext)} = 5 \Omega; I_D = 75 A; T_j = 25 °C$	-	213	-	ns
t <sub>d(off)</sub>	turn-off delay time		-	199	-	ns
t <sub>f</sub>	fall time		-	115	-	ns
Source-dra	in diode	· · · · · ·	I	1		
V <sub>SD</sub>	source-drain voltage	$I_{S}$ = 25 A; $V_{GS}$ = 0 V; $T_{j}$ = 25 °C; <u>Fig. 17</u>	-	0.8	1.2	V
t <sub>rr</sub>	reverse recovery time	$I_{\rm S}$ = 25 A; dI_{\rm S}/dt = -100 A/µs; V <sub>GS</sub> = 0 V;	-	67	-	ns
Q <sub>r</sub>	recovered charge	V <sub>DS</sub> = 15 V	-	123	-	nC



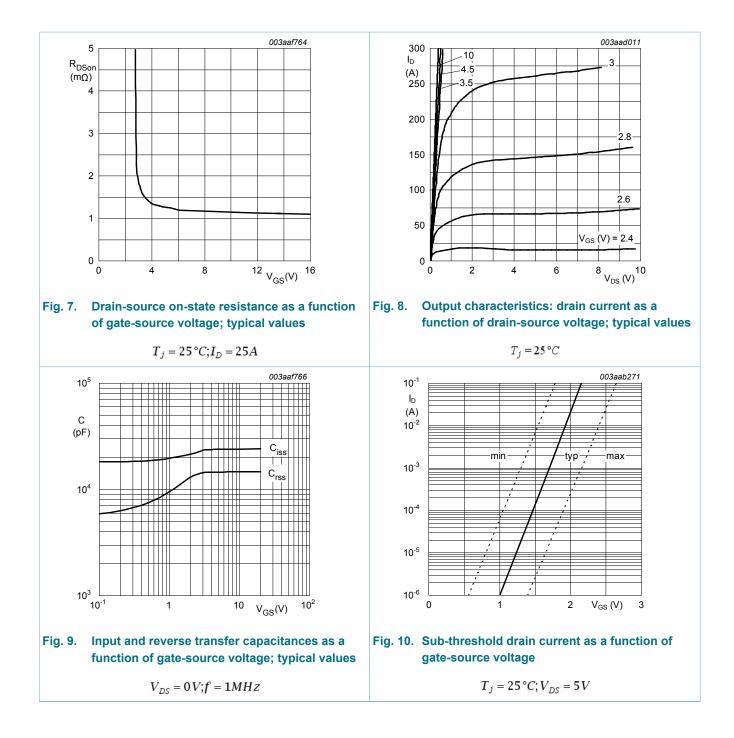


 $T_j = 25 \,^\circ C; V_{DS} = 15 V$ 



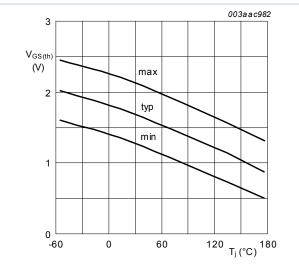
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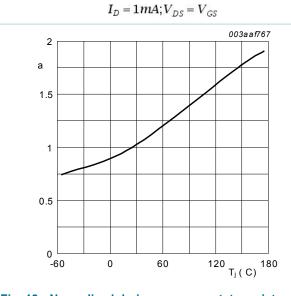


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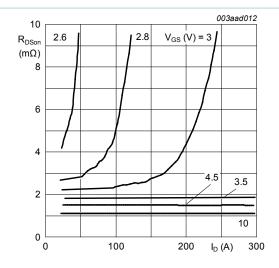








 $a = \frac{R_{DSon}}{R_{DSon(25^{\circ}C)}}$ 





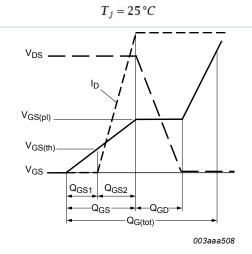
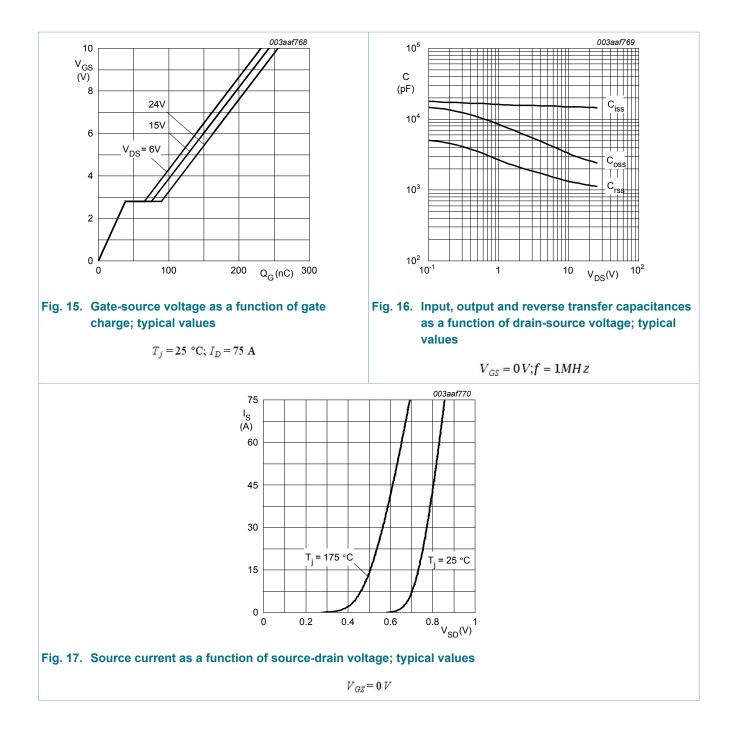


Fig. 14. Gate charge waveform definitions

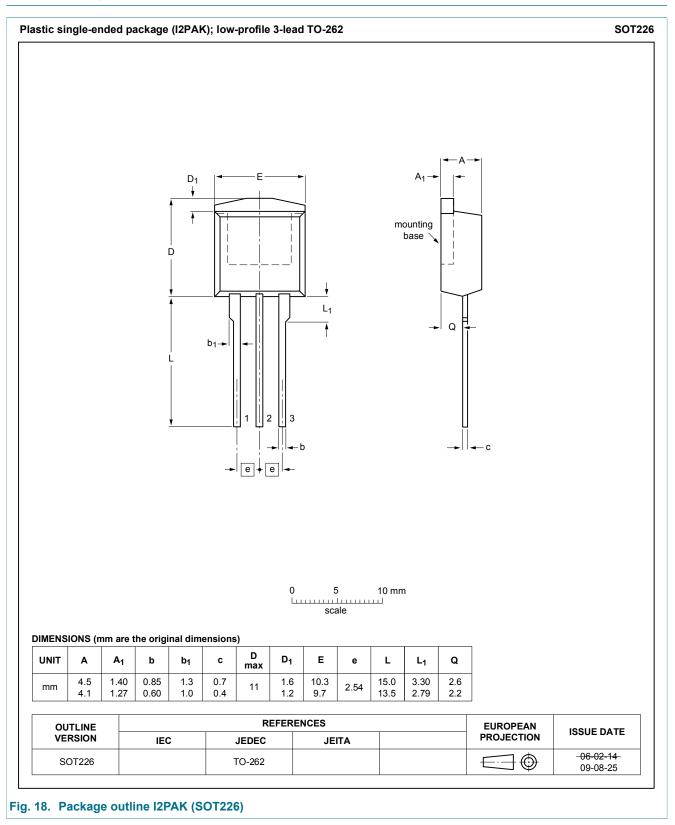
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### 11. Package outline



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